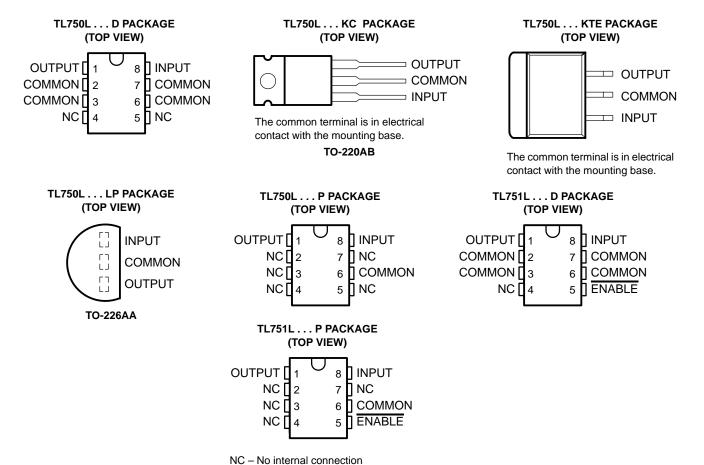
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- Very Low Dropout Voltage, Less Than 0.6 V at 150 mA
- Very Low Quiescent Current
- TTL- and CMOS-Compatible Enable on TL751L Series
- 60-V Load-Dump Protection

- Reverse Transient Protection Down to –50 V
- Internal Thermal-Overload Protection
- Overvoltage Protection
- Internal Overcurrent-Limiting Circuitry
- Less Than 500-μA Disable (TL751L Series)



description

The TL750L and TL751L series of fixed-output voltage regulators offers 5-V, 8-V, 10-V, and 12-V options. The TL751L series has the addition of an enable (ENABLE) input. When ENABLE is high, the regulator output is placed in the high-impedance state. This gives the designer complete control over power up, power down, or emergency shutdown.

The TL750L and TL751L series are low-dropout positive-voltage regulators specifically designed for battery-powered systems. These devices incorporate overvoltage and current-limiting protection circuitry, along with internal reverse-battery protection circuitry to protect the devices and the regulated system. The series is fully protected against 60-V load-dump and reverse-battery conditions. Extremely low quiescent current during full-load conditions makes these devices ideal for standby power systems.



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description (continued)

The TL750LxxC and the TL751LxxC series are characterized for operation over the virtual junction temperature range of 0°C to 125°C. The TL750L05Q and TL751L05Q are characterized for operation over the virtual junction temperature range of -40°C to 125°C.

AVAILABLE OPTIONS

	V _O TYP		PACKAGED DEVICES							
ТЈ	AT 25°C	SMALL OUTLINE (D)	HEAT-SINK MOUNTED (KC)	POWER FLEX (KTE)	PLASTIC CYLINDRICAL (LP)	PLASTIC DIP (P)				
	5 V	TL750L05CD TL751L05CD	TL750L05CKC	TL750L05CKTER	TL750L05CLP	-				
	8 V	TL750L08CD	-	_	TL750L08CLP	_				
0°C to 125°C	10 V	TL750L10CD TL751L10CD	-	-	TL750L10CLP	TL751L10CP				
	12 V	TL750L12CD TL751L12CD	ı	-	TL750L12CLP	TL751L12CP				
-40°C to 125°C	5 V	TL750L05QD TL751L05QD	-	-	-	_				

The D and LP packages are available taped and reeled. Add the suffix R to device type (e.g., TL750L05CDR). The KTE package is only available taped and reeled.

DEVICE COMPONENT COUNT					
Transistors 20					
JFETs	2				
Diodes	5				
Resistors	16				

absolute maximum ratings over operating junction temperature range (unless otherwise noted)

Continuous input voltage
Transient input voltage, T _A = 25°C (see Note 1)
Continuous reverse input voltage
Transient reverse input voltage, t ≤ 100 ms
Package thermal impedance, θ _{JA} (see Notes 2 and 3): D package
(see Notes 2 and 4): KC package
(see Notes 2 and 4): KTE package
(see Notes 2 and 3): LP package
(see Notes 2 and 3): P package
Virtual junction temperature range, T _J
Lead temperature 1,6 mm (1/16 inch) for 10 seconds
Storage temperature range, T _{stg} –65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The transient input voltage rating applies to the waveform shown in Figure 1.
 - 2. Maximum power dissipation is a function of T_J(max), θ_{JA}, and T_A. The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_J(max) - T_A)/\theta_{JA}$. Operating at the absolute maximum T_J of 150°C can affect reliability.
 - 3. The package thermal impedance is calculated in accordance with JESD 51-7.
 - 4. The package thermal impedance is calculated in accordance with JESD 51-5.



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recommended operating conditions over recommended operating junction temperature range (unless otherwise noted)

				MIN	MAX	UNITS
			TL75xL05	6	26	
 	Input voltage	TL75xL08	9	26	V	
vi	V _I Input voltage		TL75xL10	11	26	V
		TL75xL12	13	26		
VIH	V _{IH} High-level ENABLE input voltage		TL751Lxx	2	15	V
\(\(\ + \)	T _A = 25°C	T _A = 25°C	TL751Lxx	-0.3	0.8	V
V _{IL} †		T _A = full range‡	TL751Lxx	-0.15	0.8	V
IO	IO Output current range		TL75xLxx	0	150	mA
Τ.	Operating virtual junction temperature		TL75xLxxC	0	125	°C
TJ	Operating virtual junction temperature		TL75xL05Q	-40	125	C

[†] The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for ENABLE voltage levels and temperature only.

electrical characteristics, V_I = 14 V, I_O = 10 mA, T_J = 25°C (unless otherwise noted) (see Note 5)

PARAMETER	TEST CONDITIONS§		TL750L05 TL751L05			UNIT	
					TYP	MAX	
Outside and the sec	VI = 6 V to 26 V	lo - 0 to 150 m/	$T_J = 25^{\circ}C$	4.80	5	5.2	V
Output voltage	$V_{I} = 6 \text{ V to } 26 \text{ V}, \qquad I_{O} = 0 \text{ to } 150 \text{ mA}$	$T_J = 0$ °C to 125°C	4.75		5.25	V	
Input regulation voltage	V _I = 9 V to 16 V				5	10	\/
	V _I = 6 V to 26 V				6	30	mV
Ripple rejection	V _I = 8 V to 18 V,	f = 120 Hz		60	65		dB
Output regulation voltage	I _O = 5 mA to 150 mA				20	50	mV
Dropout voltage	I _O = 10 mA					0.2	V
Dropout voltage	I _O = 150 mA					0.6	V
Output noise voltage	f = 10 Hz to 100 kHz				500		μV
	I _O = 150 mA				10	12	
Input bias current	$V_{I} = 6 \text{ V to } 26 \text{ V},$	$I_{O} = 10 \text{ mA},$	T」= TJ(min) to 125°C¶		1	2	mA
	ENABLE > 2 V	_				0.5	

[§] Pulse-testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1- μ F capacitor across the input and a 10- μ F capacitor, with equivalent series resistance of less than 0.4 Ω , across the output.

NOTE 5: For TL750L05Q/TL751L05Q, all characteristics are measured with a 10-μF tantalum capacitor on the output, with equivalent series resistance within the guidelines shown in Figure 4.



[‡] Full range is 0°C to 125°C for the TL75xLxxC devices and –40°C to 125°C for the TL75L05Q devices.

[¶]T_J(min) is 0°C for the TL75xLxxC devices and -40°C for the TL75xLxxQ devices.

TL750L, TL751L SERIES LOW-DROPOUT VOLTAGE REGULATORS

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electrical characteristics, $V_I = 14 \text{ V}$, $I_O = 10 \text{ mA}$, $T_J = 25^{\circ}\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]			TL750L08 TL751L08			UNIT	
				MIN	TYP	MAX		
Output voltage	V _I = 9 V to 26 V,	I _O = 0 to 150 mA	$T_J = 25^{\circ}C$	7.68	8	8.32	V	
Output voitage	V = 9 V 10 20 V,	IQ = 0 to 150 IIIA	T _J = 0°C to 125°C	7.6		8.4	V	
Input regulation voltage	V _I = 10 V to 17 V				10	20	m\/	
Input regulation voltage	V _I = 9 V to 26 V				25	50	mV	
Ripple rejection	V _I = 11 V to 21 V,	f = 120 Hz		60	65		dB	
Output regulation voltage	$I_O = 5 \text{ mA to } 150 \text{ mA}$				40	80	mV	
Dropout voltage	I _O = 10 mA					0.2	V	
Dropout voltage	I _O = 150 mA					0.6	V	
Output noise voltage	f = 10 Hz to 100 kHz				500		μV	
	I _O = 150 mA				10	12		
Input bias current	V _I = 9 V to 26 V,	I _O = 10 mA,	$T_J = 0$ °C to 125°C		1	2	mA	
	ENABLE > 2 V					0.5		

 $[\]bar{T}$ Pulse-testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1- μ F capacitor across the input and a 10- μ F capacitor, with equivalent series resistance of less than 0.4 Ω , across the output.

electrical characteristics, $V_I = 14 \text{ V}$, $I_O = 10 \text{ mA}$, $T_J = 25^{\circ}\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]			TL750L10 TL751L10			UNIT	
					TYP	MAX		
Output valtage	V _I = 11 V to 26 V,	I _O = 0 to 150 mA	T _J = 25°C	9.6	10	10.4	٧	
Output voltage		10 = 0 to 130 mA	$T_{J} = 0^{\circ}C \text{ to } 125^{\circ}C$	9.5		10.5	V	
Input regulation voltage	V _I = 12 V to 19 V				10	25	mV	
Input regulation voltage	V _I = 11 V to 26 V				30	60	IIIV	
Ripple rejection	V _I = 12 V to 22 V,	f = 120 Hz		60	65		dB	
Output regulation voltage	$I_O = 5 \text{ mA to } 150 \text{ mA}$				50	100	mV	
Dropout voltage	I _O = 10 mA					0.2	V	
Dropout voltage	I _O = 150 mA					0.6	V	
Output noise voltage	f = 10 Hz to 100 kHz				700		μV	
	I _O = 150 mA				10	12		
Input bias current	V _I = 11 V to 26 V,	$I_{O} = 10 \text{ mA},$	$T_J = 0^{\circ}C$ to $125^{\circ}C$		1	2	mA	
	ENABLE > 2 V		_			0.5		

[†] Pulse-testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1- μ F capacitor across the input and a 10- μ F capacitor, with equivalent series resistance of less than 0.4 Ω , across the output.

TL750L, TL751L SERIES LOW-DROPOUT VOLTAGE REGULATORS

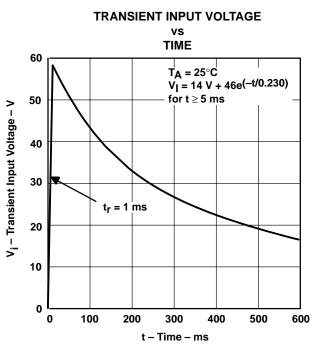
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electrical characteristics, V_I = 14 V, I_O = 10 mA, T_J = 25°C (unless otherwise noted)

PARAMETER	TEST CONDITIONS	TEST CONDITIONS†			TL750L12 TL751L12		
			MIN	TYP	MAX		
Output voltage	V _I = 13 V to 26 V, I _O = 0 to 150 mA	T _J = 25°C	11.52	12	12.48	V	
Output voltage	V = 13 V to 26 V, IO = 0 to 150 IIIA	$T_J = 0$ °C to 125°C		V			
lanut regulation valtage	V _I = 14 V to 19 V			15	30	>/	
Input regulation voltage	V _I = 13 V to 26 V	V _I = 13 V to 26 V			40	mV	
Ripple rejection	V _I = 13 V to 23 V, f = 120 Hz	V _I = 13 V to 23 V, f = 120 Hz				dB	
Output regulation voltage	I _O = 5 mA to 150 mA	I _O = 5 mA to 150 mA			120	mV	
Dranaut valtage	I _O = 10 mA	I _O = 10 mA			0.2	V	
Dropout voltage	$I_{O} = 150 \text{ mA}$	I _O = 150 mA			0.6	V	
Output noise voltage	f = 10 Hz to 100 kHz	f = 10 Hz to 100 kHz				μV	
	I _O = 150 mA			10	12		
Input bias current	$V_I = 13 \text{ V to } 26 \text{ V}, I_O = 10 \text{ mA},$	$V_{I} = 13 \text{ V to } 26 \text{ V}, I_{O} = 10 \text{ mA}, \qquad T_{J} = 0^{\circ}\text{C to } 125^{\circ}\text{C}$			2	mA	
	ENABLE > 2 V	ENABLE > 2 V			0.5		

[†] Pulse-testing techniques are used to maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1- μ F capacitor across the input and a 10- μ F capacitor, with equivalent series resistance of less than $0.4~\Omega$, across the output.

TYPICAL CHARACTERISTICS



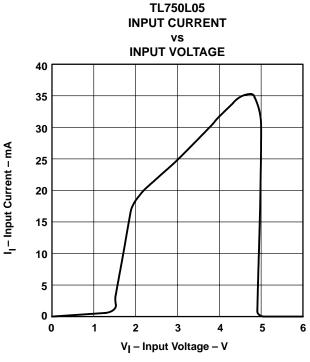
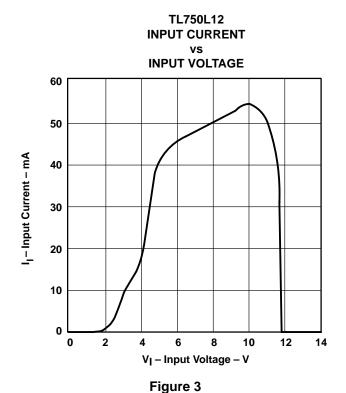


Figure 1

Figure 2



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TYPICAL CHARACTERISTICS

TL750L05 EQUIVALENT SERIES RESISTANCE

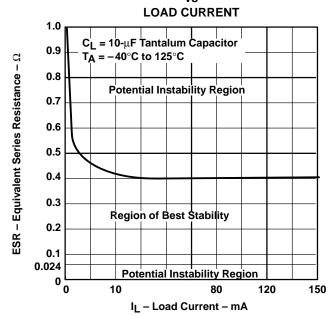


Figure 4

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